

Judul:

ISTFA 2008: conference proceedings from the 34th International Symposium for Testing and Failure Analysis, November 2-6, 2008, Oregon Convention Center, Portland, Oregon, USA

Pengarang/Penulis:

Subjek:

Electronics -- Materials -- Testing -- Congresses; Electronic apparatus and appliances -- Testing -- Congresses.

Nomor Panggil:

e20442550

Penerbitan:

ASM International

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